(EAP1018B-0316-EC)

MFG Test Plan

EAP1018B-0316-EC

Version: V1.0

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Revision History

Rev.	Date	Author	Revision Description
1.0	2016/07/07	Alan	1st Release
			1.

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1. Purpose

This document describes how EAP1018B-0316-EC is Tested in production line in order to maintain the good quality for shipment

2. Scope

Follow up the Test Plan and sync with all member include MFG. Development team and customer side can well understanding and follow up to maintain the good quality for shipment

3. Reference Documents

EAP1018B-0316-EC TestPlan V1.0

4. Acronyms

DUT	Device Under Test
ART	Atheros Radio Test
AOI	Automated Optical Inspection
PER	Packet Error Rate
PT	Pre-Test
B/I	Burn-In Test
PK	Package
ICT	In Circuit Test
MFG	manufacturing
BFT	Board Final Test
SFT	system Final Test
SMT	Surface Mount Technology
POST	Power On Self Test
MP	Mass Production
DFT	Design For Testing
DIP	dual in-line package
Diag	One part of DUT application and inside of the flash. It exercises chipset

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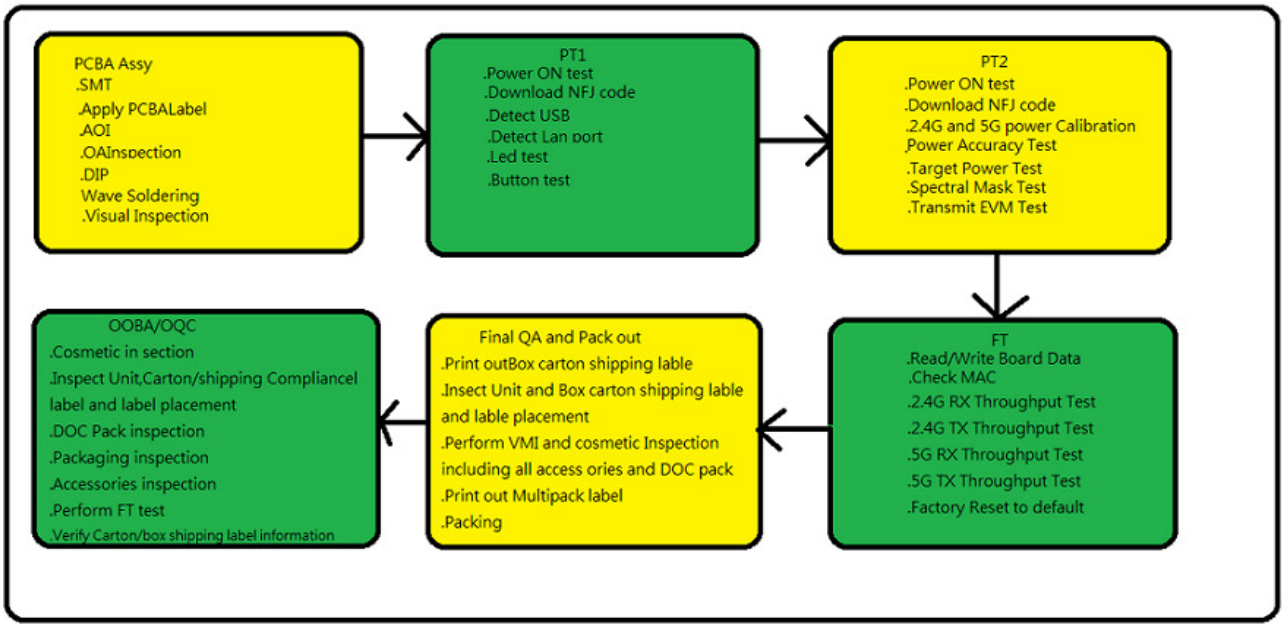
register; verify HW interface and this is DFT implementation for EVT,DVT,and MFG testing. User can initial Diag entry by specific procedure. The end-user will not able to it.

5. Introduction

5.1 Production Test Flow Diagram



A general test process flow for the EAP1018B-0316-EC includes:

- PT: Digit Test (Led Test,Button Test,Ethernet Test), RF Function Test,Read/Write SN MAC
- FT: 2.4G Tx/Rx Throughput, 5G Tx/Rx Throughput
- Final QA and Pack out
- Out of Box Audit

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6. Board Level Functional Test

6.1 PT Test Environment Setup

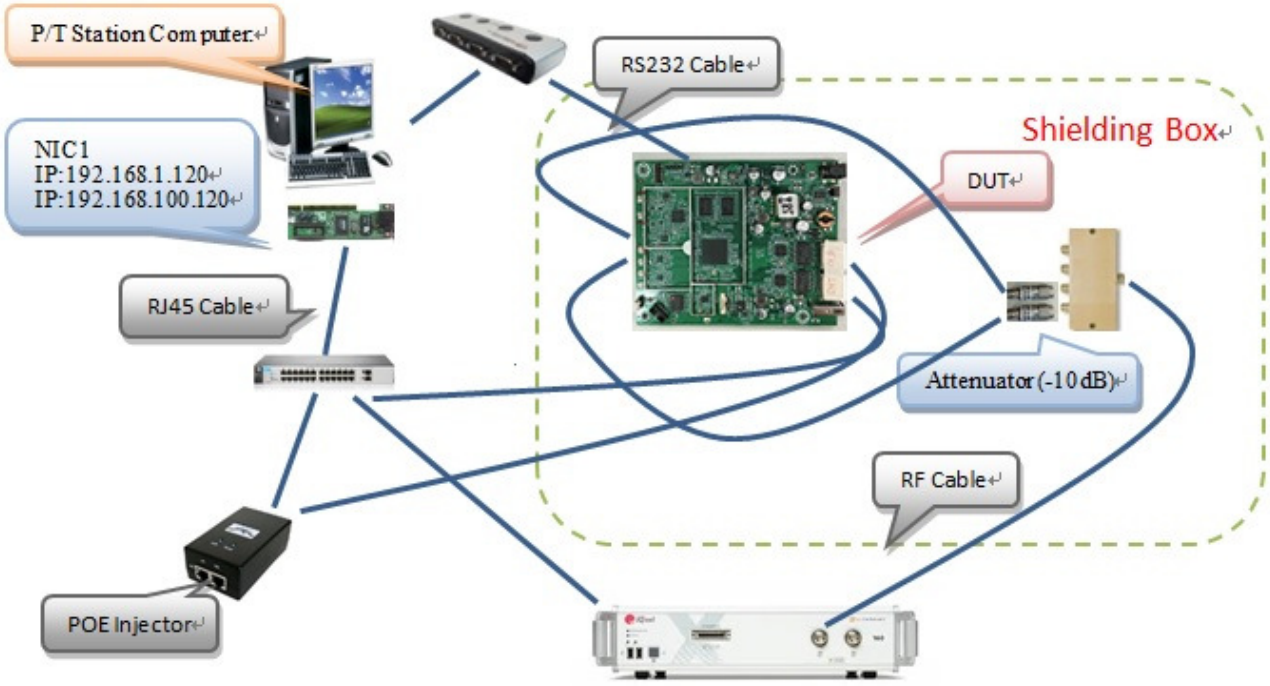

Figure 錯誤! 所指定的樣式的文字不存在文件中。**-1** Board Level Test Setup Configuration

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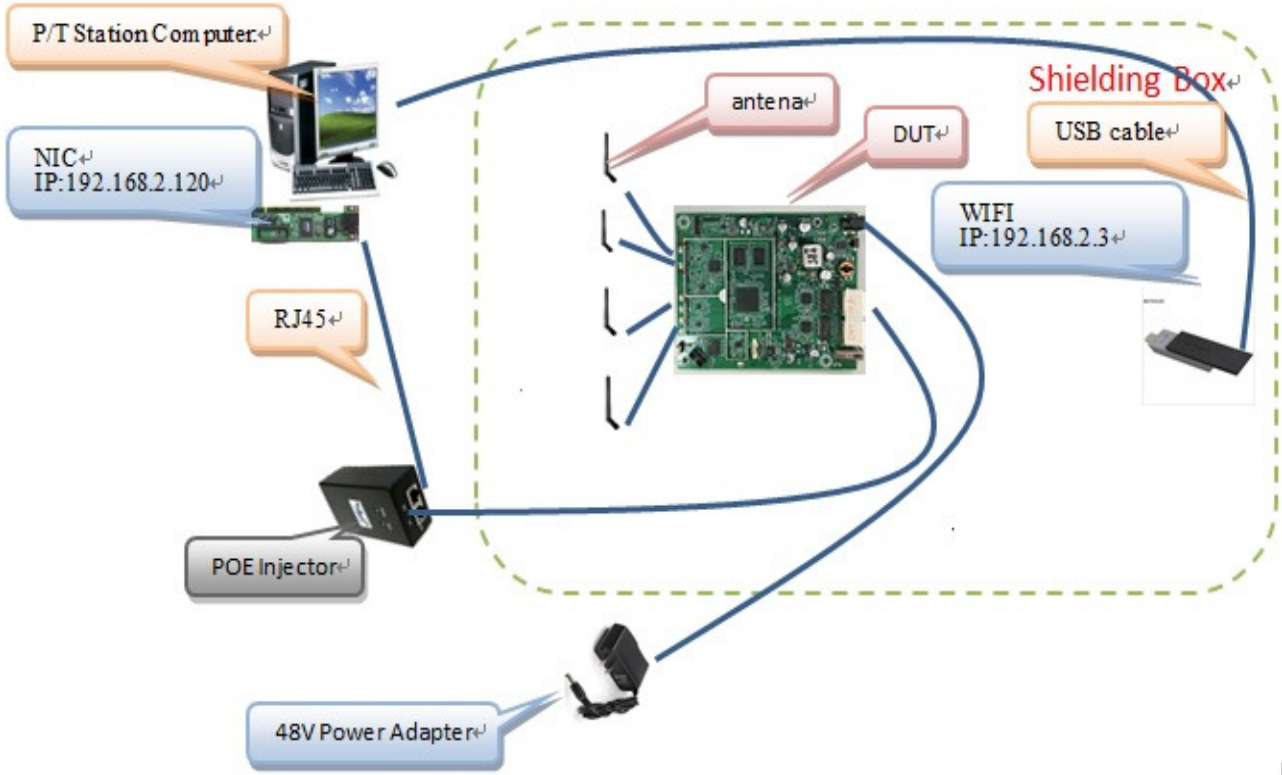
6.2 FT Test Environment Setup



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6.3 Hardware Requirement

- Pentium PC (or above) running Win7 32bit
- RS232 Console Board / cable x 1
- DC Adaptor 12V/2A x 1
- Shielding Box x 1
- IQxel(IQ80)
- Attenuator 10dB x 4
- POE x 1
- RF Cable x N
- Ethernet cable x N
- Wireless card x 1
- 5 G Attena x 1
- 2.4 G Attena x 1

6.4 Software Requirement

Microsoft OS Windows 7 32 bit

ActiveTCL: Tcl v8.5.xx

VC++ 2005 (IQxel)

VC++ 2008 (IQxel)

VC++ 2012 (IQxel)

MCR7.9 (IQxel)

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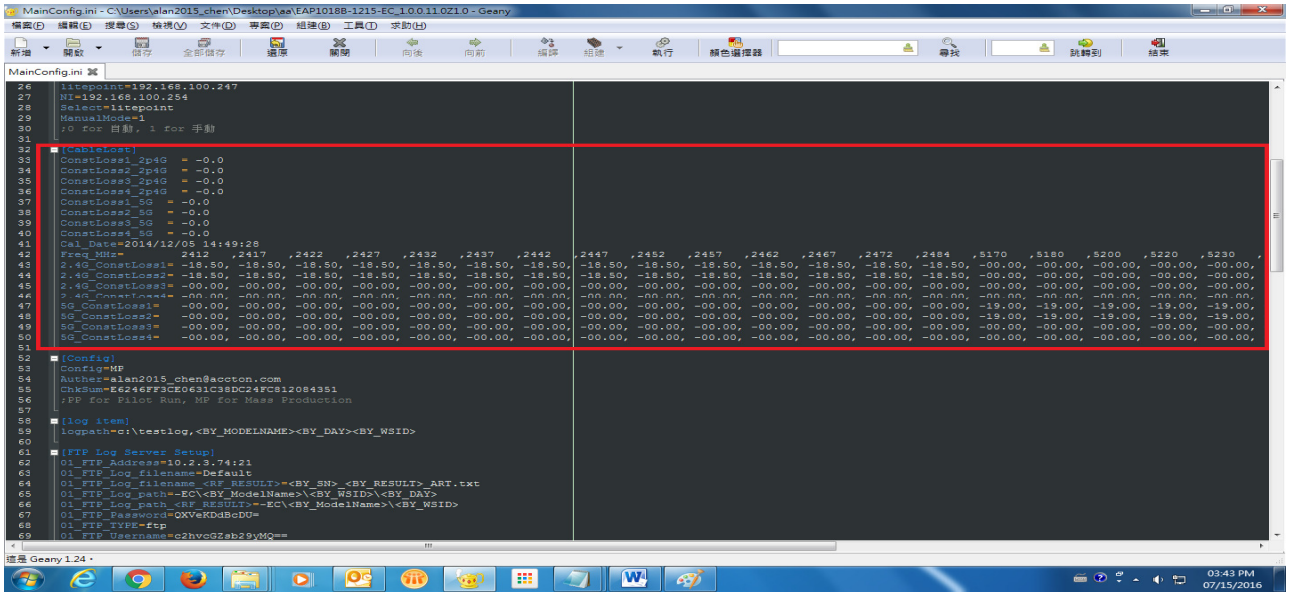
6.5 Test Program Environment Setup

1. 設定 Cable Loss

   2G 使用 2.4G_ConstLoss1, 2.4G_ConstLoss2

   5G 使用 5G_ConstLoss1, 5G_ConstLoss2



2. 設定 IQxel IP 位置

   在 MainConfig.ini 中 Equipment->litepoint 修改 IQxel IP 位置

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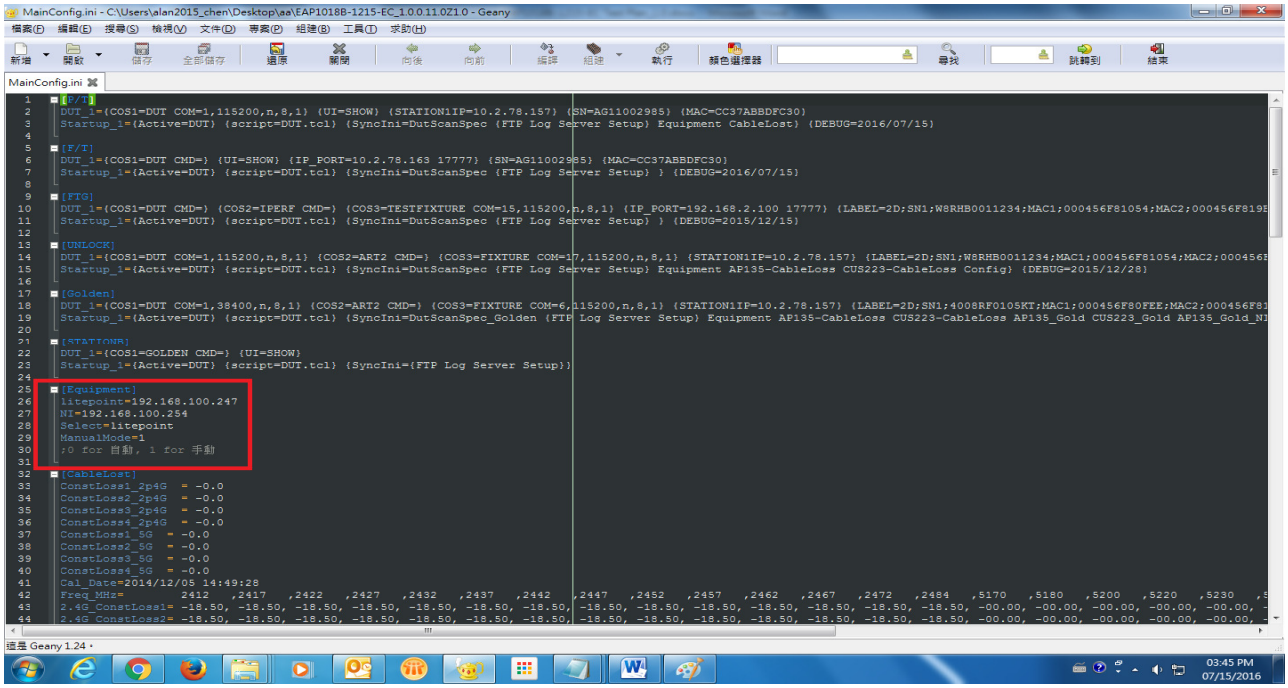

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